



General Description:

HPD700R1K3SA, the silicon N-channel Enhanced MOSFETs, is obtained by the super junction technology which reduces the conduction loss, improve switching performance and enhance the avalanche energy. The transistor can be used in various power switching circuit for system miniaturization and higher efficiency. The package type is TO-252, which accords with the RoHS standard.

Features:

- Fast Switching
- Low Gate Charge
- Low Reverse transfer capacitances
- 100% Single Pulse avalanche energy Test

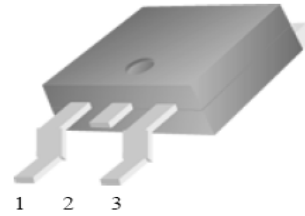
Applications:

Power switch circuit of adaptor and charger.

Absolute (Tc= 25°C unless otherwise specified):

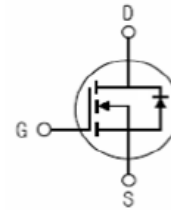
V_{DSS}	700	V
I_D	6	A
$P_D(T_C=25^{\circ}C)$	94	W
$R_{DS(ON)Typ}$	0.95	Ω

TO-252



1.Gate 2.Drain 3.Source

Inner Equivalent Principium Chart



Symbol	Parameter	Rating	Units
V_{DSS}	Drain-to-Source Voltage($V_{GS}=0V$)	700	V
I_D	Continuous Drain Current	6	A
I_{DM}^{a1}	Pulsed Drain Current	18	A
V_{GSS}	Gate-to-Source Voltage	± 30	V
E_{AS}^{a2}	Single Pulse Avalanche Energy	50	mJ
dv/dt^{a3}	Peak Diode Recovery dv/dt	5	V/ns
P_D	Power Dissipation(T=25°C)	94	W
T_J, T_{stg}	Operating and Storage Temperature Range	-55...+150	°C
T_L	Maximum Temperature for Soldering	300	°C

**Electrical Characteristics** (Tc= 25℃ unless otherwise specified):

OFF Characteristics						
Symbol	Parameter	Test Conditions	Rating			Units
			Min.	Typ.	Max.	
V _{DSS}	Drain to Source Breakdown Voltage	V _{GS} =0V, I _D =250μA	700	--	--	V
Δ BV _{DSS} / Δ T _J	Bvdss Temperature Coefficient	ID=250uA, Reference 25℃	--	0.67	--	V/℃
I _{DSS}	Drain to Source Leakage Current	V _{DS} = 700V, V _{GS} = 0V, T _a = 25℃	--	--	1	μA
		V _{DS} =560V, V _{GS} = 0V, T _a = 125℃	--	--	100	
I _{GSS(F)}	Gate to Source Forward Leakage	V _{GS} =+30V	--	--	100	nA
I _{GSS(R)}	Gate to Source Reverse Leakage	V _{GS} =-30V	--	--	-100	nA

ON Characteristics						
Symbol	Parameter	Test Conditions	Rating			Units
			Min.	Typ.	Max.	
R _{DS(ON)}	Drain-to-Source On-Resistance	V _{GS} =10V, I _D =2.8A	--	0.95	1.3	Ω
V _{GS(TH)}	Gate Threshold Voltage	V _{DS} = V _{GS} , I _D = 250μA	2	--	4	V
Pulse width tp ≤ 300μs, δ ≤ 2%						

Dynamic Characteristics						
Symbol	Parameter	Test Conditions	Rating			Units
			Min.	Typ.	Max.	
C _{iss}	Input Capacitance	V _{GS} = 0V V _{DS} = 25V f = 1.0MHz	--	416	--	pF
C _{oss}	Output Capacitance		--	368	--	
C _{rss}	Reverse Transfer Capacitance		--	13.8	--	

Resistive Switching Characteristics						
Symbol	Parameter	Test Conditions	Rating			Units
			Min.	Typ.	Max.	
t _{d(ON)}	Turn-on Delay Time	I _D = 6A V _{DD} = 400V R _G =10Ω	--	15	42	ns
t _r	Rise Time		--	20	60	
t _{d(OFF)}	Turn-Off Delay Time		--	38	80	
t _f	Fall Time		--	9	32	
Q _g	Total Gate Charge	I _D =6A V _{DD} =560V V _{GS} = 10V	--	16.9	--	nC
Q _{gs}	Gate to Source Charge		--	3	--	
Q _{gd}	Gate to Drain (“Miller”)Charge		--	9.2	--	



Source-Drain Diode Characteristics						
Symbol	Parameter	Test Conditions	Rating			Units
			Min.	Typ.	Max.	
I_S	Continuous Source Current (Body Diode)	$T_C=25^{\circ}\text{C}$	--		6	A
I_{SM}	Maximum Pulsed Current (Body Diode)		--		18	A
V_{SD}	Diode Forward Voltage	$I_S=6\text{A}, V_{GS}=0\text{V}$	--	0.9	1.2	V
t_{rr}	Reverse Recovery Time	$I_F=I_S \quad T_j = 25^{\circ}\text{C}$ $dI_F/dt=100\text{A}/\mu\text{s},$ $V_{GS}=0\text{V s}$	--	282	--	ns
Q_{rr}	Reverse Recovery Charge		--	1.96	--	uC
I_{RRM}	Reverse Recovery Current			0.9	1.2	A

Symbol	Parameter	Typ.	Units
$R_{\theta JC}$	Junction-to-Case	1.32	$^{\circ}\text{C}/\text{W}$
$R_{\theta JA}$	Junction-to-Ambient	100	$^{\circ}\text{C}/\text{W}$

^{a1}: Repetitive rating; pulse width limited by maximum junction temperature

^{a2}: $L=20.0\text{mH}$, $R_g=25\ \Omega$, $V_{dd}=50\text{V}$, Start $T_j=25^{\circ}\text{C}$

^{a3}: $I_{SD}=6\text{A}$, $di/dt \leq 100\text{A}/\mu\text{s}$, $V_{DD} \leq BV_{DS}$, Start $T_j=25^{\circ}\text{C}$

Characteristics Curve:

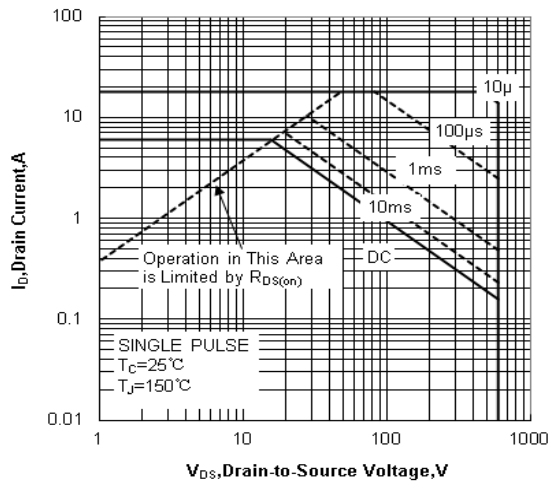


Figure.1 Maximum Forward Bias Safe Operating Area

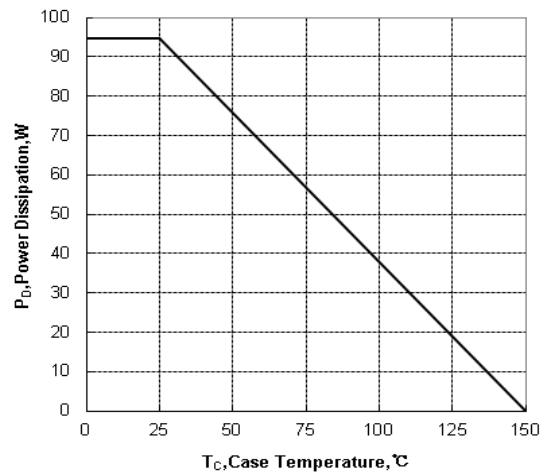


Figure.2 Maximum Power Dissipation vs Case Temperature

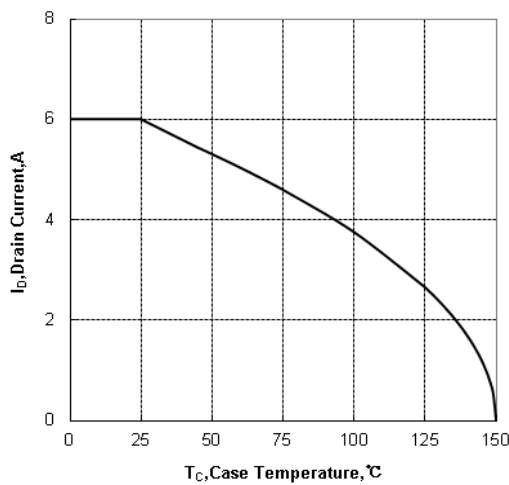


Figure.3 Maximum Continuous Drain Current vs Case Temperature

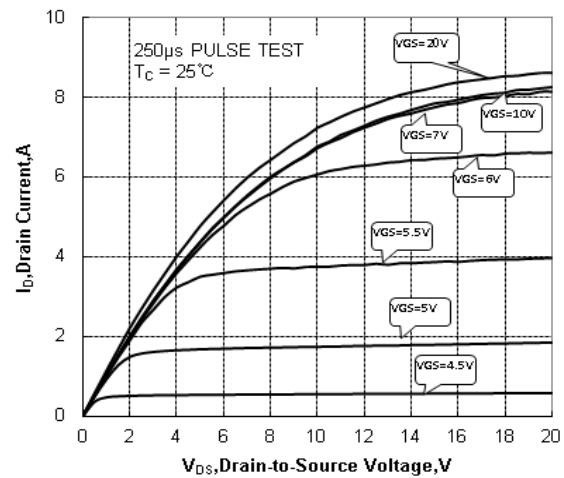


Figure.4 Typical Output Characteristics

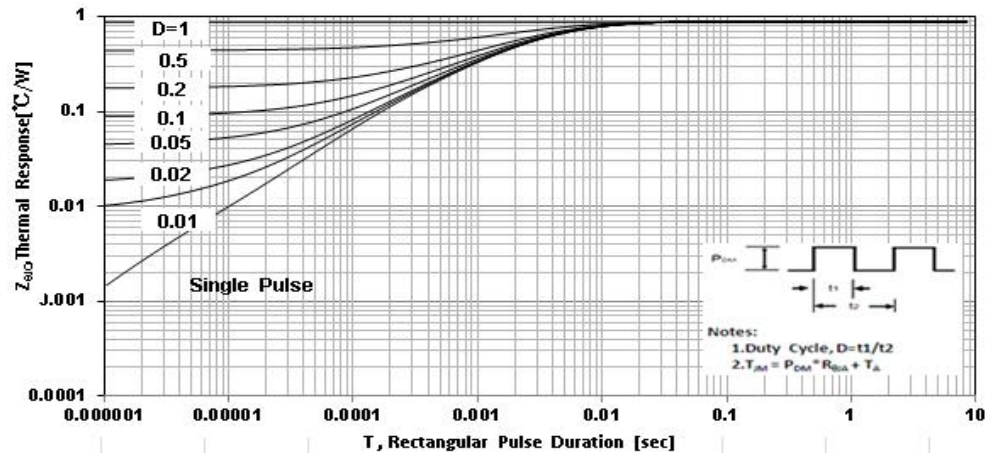


Figure.5 Maximum Effective Thermal Impedance , Junction to Case

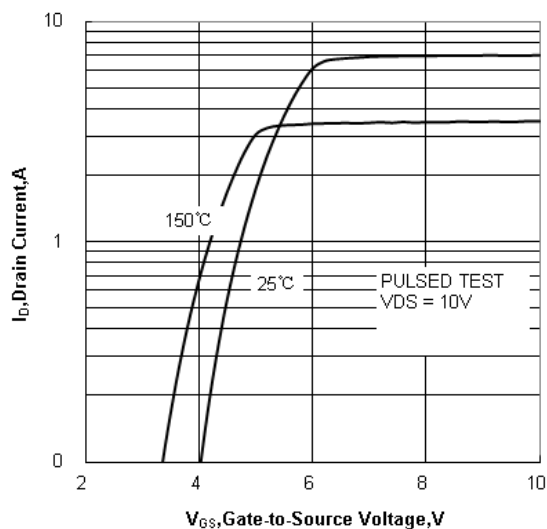


Figure.6 Typical Transfer Characteristics

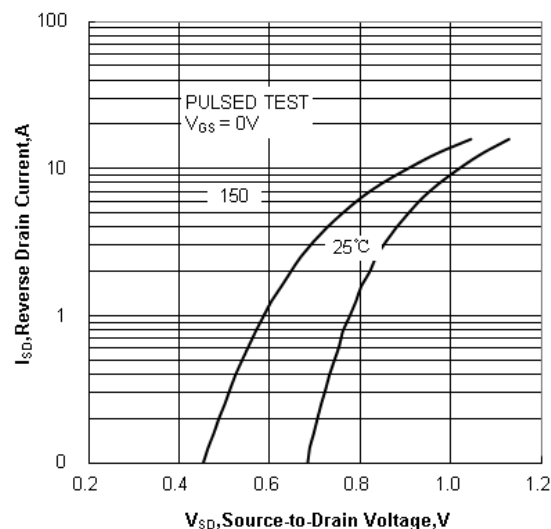


Figure.7 Typical Body Diode Transfer Characteristics

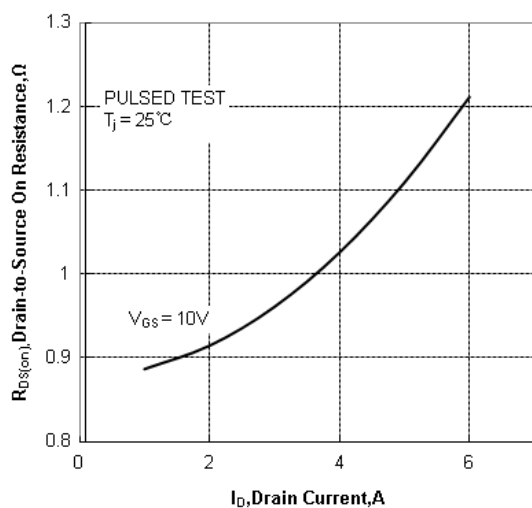


Figure.8 Typical Drain to Source ON Resistance vs Drain Current

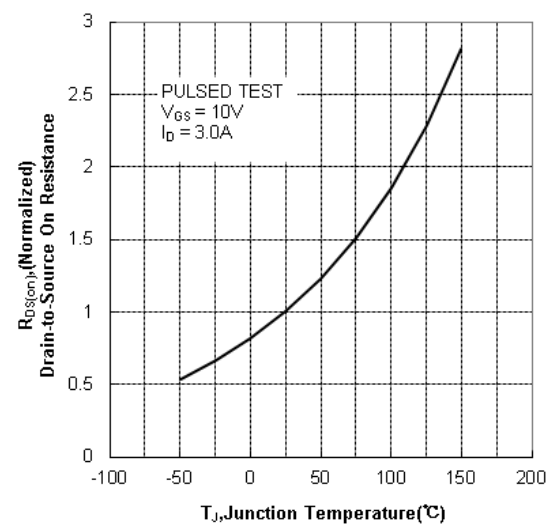


Figure.9 Typical Drain to Source on Resistance vs Junction Temperature

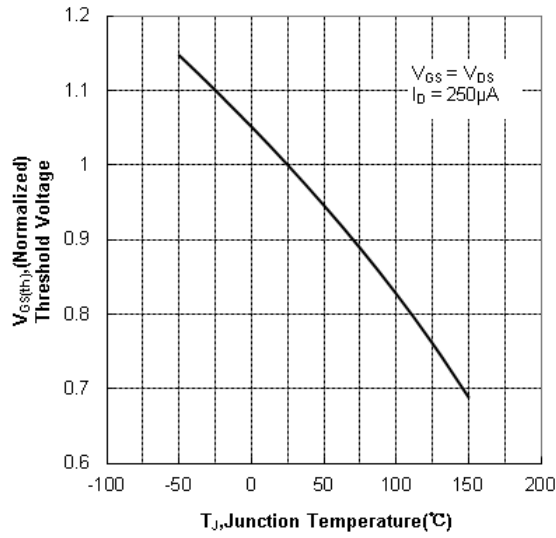


Figure.10 Typical Theshold Voltage vs Junction Temperatu

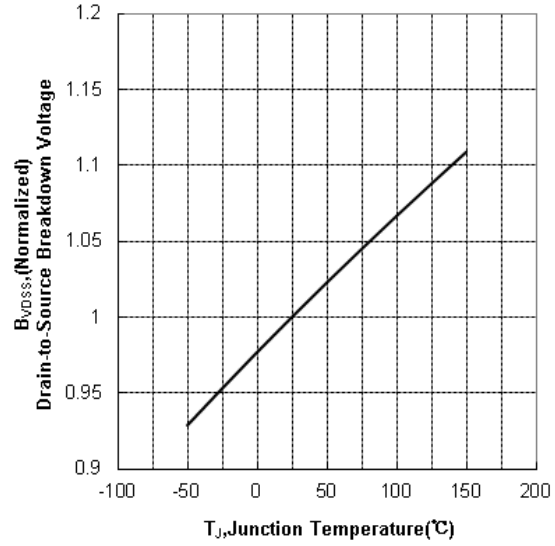


Figure 11 Typical Breakdown Voltage vs Junction Temperature

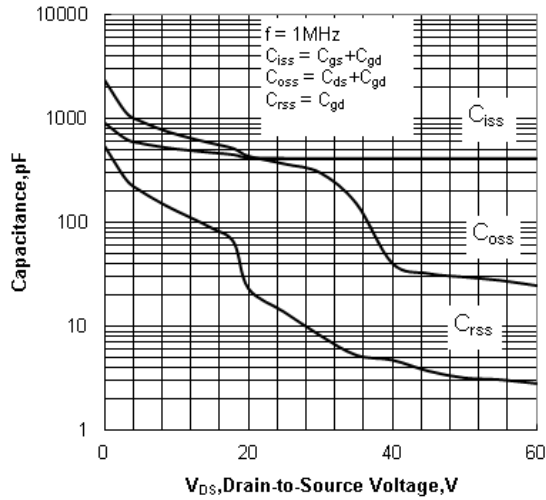


Figure.12 Typical Capacitance vs Drain to Source Voltage

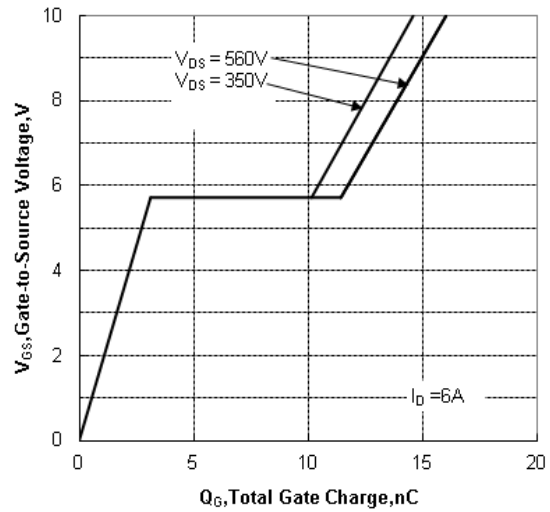


Figure.13 Typical Gate Charge vs Gate to Source Voltage

Test Circuit and Waveform

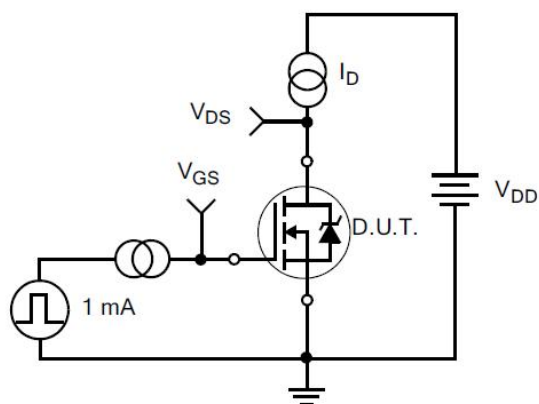


Figure 17. Gate Charge Test Circuit

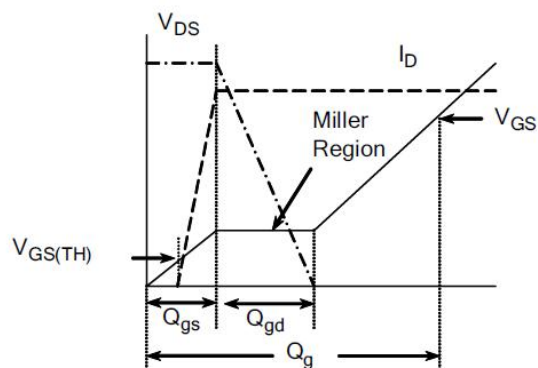


Figure 18. Gate Charge Waveform

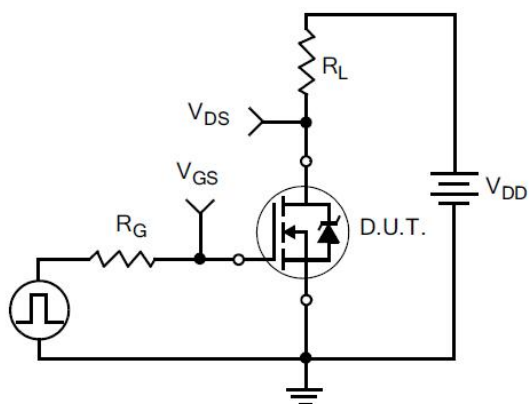


Figure 19. Resistive Switching Test Circuit

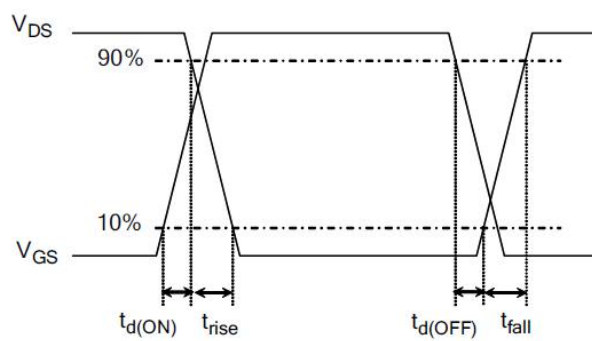


Figure 20. Resistive Switching Waveforms

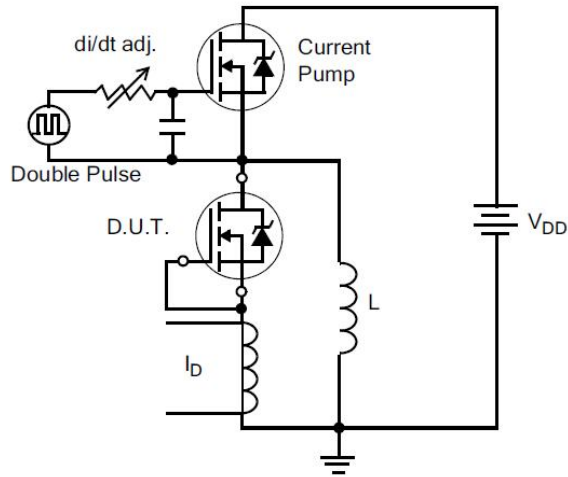


Figure 21. Diode Reverse Recovery Test Circuit

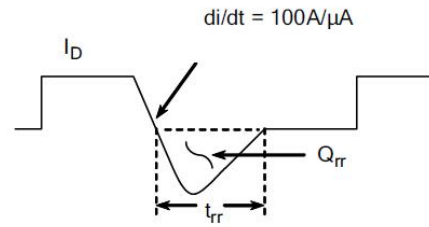


Figure 22. Diode Reverse Recovery Waveform

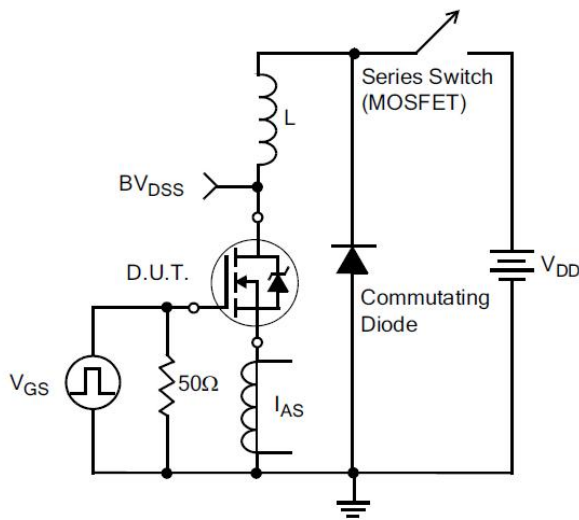


Figure 23. Unclamped Inductive Switching Test Circuit

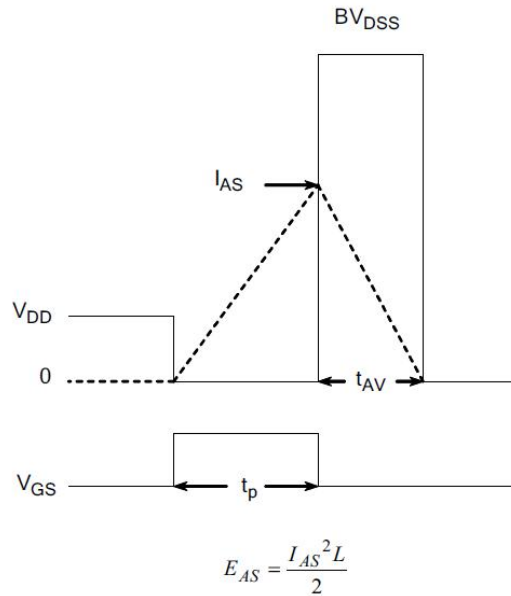
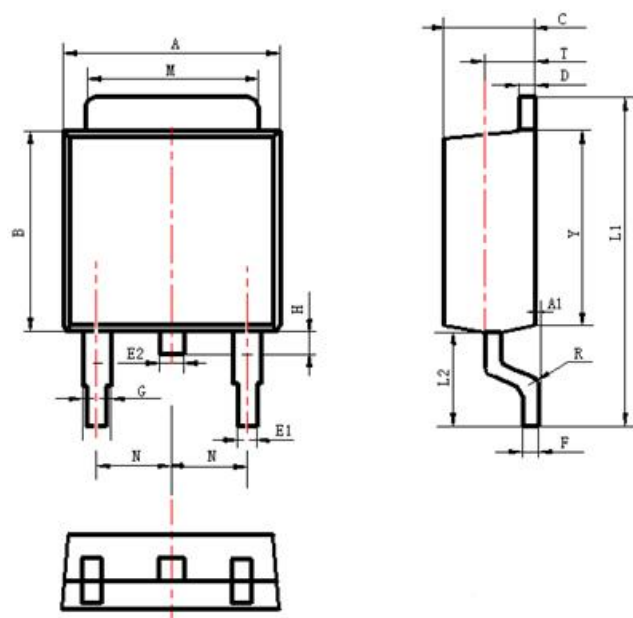


Figure 24. Unclamped Inductive Switching Waveforms

Package Information



Items	Values(mm)	
	MIN	MAX
A	6.30	6.90
A1	0	0.13
B	5.70	6.30
C	2.10	2.50
D	0.30	0.60
E1	0.60	0.90
E2	0.70	1.00
F	0.30	0.60
G	0.70	1.20
L1	9.60	10.50
L2	2.70	3.10
H	0.60	1.00
M	5.10	5.50
N	2.09	2.49
R	0.3	
T	1.40	1.60
Y	5.10	6.30

TO-252 Package

**The name and content of poisonous and harmful material in products**

	Hazardous Substance									
	Pb	Hg	Cd	Cr(VI)	PBB	PBDE	DIBP	DEHP	DBP	BBP
Limit	≤0.1%	≤0.1%	≤0.01%	≤0.1%	≤0.1%	≤0.1%	≤0.1%	≤0.1%	≤0.1%	≤0.1%
Lead Frame	○	○	○	○	○	○	○	○	○	○
Molding	○	○	○	○	○	○	○	○	○	○
Chip	○	○	○	○	○	○	○	○	○	○
Wire Bonding	○	○	○	○	○	○	○	○	○	○
Solder	×	○	○	○	○	○	○	○	○	○
Note	○: Means the hazardous material is under the criterion of 2011/65/EU. ×: Means the hazardous material exceeds the criterion of 2011/65/EU. The plumbum element of solder exist in products presently, but within the allowed range of Eurogroup's RoHS.									

Warnings

1. Exceeding the maximum ratings of the device in performance may cause damage to the device, even the permanent failure, which may affect the dependability of the machine. It is suggested to be used under 80 percent of the maximum ratings of the device.
2. When installing the heat sink, please pay attention to the torsional moment and the smoothness of the heatsink.
3. VDMOSFET is the device which is sensitive to the static electricity, it is necessary to protect the device from being damaged by the static electricity when using it.
4. This publication is made by Huajing Microelectronics and subject to regular change without notice.

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